

Patent claims

1. A method for the monitoring of a manufacturing process
of a plurality of physical objects,
5 in which an analysis is performed by using values of
at least one process parameter of the manufacturing
process of the physical object;
in which, as a result of the analysis, when they do
not satisfy a prescribed selection criterion, physical
10 objects are marked in such a way that the associated
physical objects are to be sent for a special
measurement.
2. The method as claimed in claim 1, in which the
15 physical object is a wafer.
3. The method as claimed in claim 1 or 2, in which the
analysis is a statistical analysis.
- 20 4. The method as claimed in one of claims 1 to 3, in
which the values of the at least one process parameter
are measured when the physical object is being
manufactured.
- 25 5. The method as claimed in one of claims 1 to 4, in
which at least one marked physical object is sent for
a special measurement.
- 30 6. The method as claimed in claim 5, in which the special
measurement is a measurement for checking the quality
of the physical object marked.
7. The method as claimed in one of claims 1 to 6, in
which the physical objects not marked are further
35 treated according to the manufacturing process.

8. The method as claimed in one of claims 1 to 7, in which the selection criterion is a quality characteristic of the manufacturing process.
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9. The method as claimed in one of claims 1 to 8, in which the selection criterion is considered as not satisfied if a value of the at least one process parameter goes above or below a prescribed limit value.
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10. A device for the monitoring of a manufacturing process of a plurality of physical objects with a processor which is set up in such a way that the following method steps can be carried out:
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- performance of an analysis by using values of at least one process parameter of the manufacturing process of the physical object;
- marking of physical objects when, as a result of the analysis, a prescribed selection criterion is not
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- satisfied, so that the associated physical objects are to be sent for special treatments.
11. A computer-readable storage medium, in which a program
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- for the monitoring of a manufacturing process of a plurality of physical objects is stored, which program has the following method steps when it is run by a processor:
- performance of an analysis by using values of at least
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- one process parameter of the manufacturing process of the physical object;
- marking of physical objects when, as a result of the analysis, a prescribed selection criterion is not
- satisfied, so that the associated physical objects are
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- to be sent for special treatments.

12. A computer program element for the monitoring of a manufacturing process of a plurality of physical objects, which has the following method steps when it is run by a processor:
- 5 performance of an analysis by using values of at least one process parameter of the manufacturing process of the physical object;
- 10 marking of physical objects when, as a result of the analysis, a prescribed selection criterion is not satisfied, so that the associated physical objects are to be sent for special treatments.
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